



Contactless Resistivity / Thickness, Sheet Resistance 100mm - 300mm Silicon



LEI RS300 (300 mm Robotic Sorting) shown with 2 cassettes (product may differ from photo)

Features:

- Non-destructive characterization of 200mm and 300mm Si wafers
- GEM/SECSII compliance
- LEI Windows NT Software (standard)
- HERMOS available
- Bar-code scanning availability
- Scanning end effector

RS300



*Process Monitoring & Quality Control
for High Production Yields.*

“We estimate we save a minimum of \$250K per year by having the Leighton systems.”

-Dr. Martin J. Brophy
Senior Process Engineer for Wafers/Implant/Anneal
TriQuint Semiconductor

Performance:*

| | Bulk Resistivity | Linearity (Repeatability) | Standard Deviation (sheet resistance) | Standard Deviation (bulk resistivity) |
|-----------|------------------|---------------------------|---------------------------------------|---------------------------------------|
| HI | 200 ohm-cm | 3% | 1.0 % | 2.01 % |
| | 100 ohm-cm | 3% | 0.5% | 1.75% |
| | 25 ohm-cm | 3% | 0.1% | 1.55% |
| | 10 ohm-cm | 3% | 0.1% | 1.55% |
| | 1 ohm-cm | 3% | 0.1% | 1.55% |
| LO | 1 ohm-cm | 3% | 1.0% | 2.01% |
| | 0.1 ohm-cm | 3% | 0.20% | 1.60% |
| | 0.01 ohm-cm | 3% | 0.25% | 1.63% |
| XL | 0.1 ohm-cm | 3% | 0.7% | 1.86% |
| | 0.01 ohm-cm | 3% | 0.55% | 1.78% |
| | 0.005 ohm-cm | 3% | 0.55% | 1.78% |
| | 0.002 ohm-cm | 3% | 0.55% | 1.78% |

*(Conforms to ASTM F673) Based on average of a repeat 10 center-point test of a NIST-traceable, uniformly doped silicon standard (where available). NIST wafers available for calibration.

Throughput:

- 55 measurement sites in 2.5 minutes
- User-definable test plans (up to 200 meas. sites)

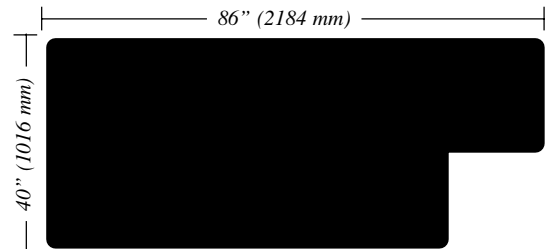
Facility Requirements:

- **Voltage**
100-120 VAC ± 50-60 Hz
220-240 VAC ± 50-60 Hz
- **Vacuum**
400-600 mm Hg

For More Information:

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Footprint:



Thickness:

- **Range**
700-800µmm*
- **Repeatability**
Resolution to 0.1 µm

*extended thickness ranges available on request